## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10825575	HEINONEN ET AL.
Examiner	Art Unit
Kowalewski, Filip A Kai Rajan	3736

SEARCHED					
Class	Subclass	Date	Examiner		
600	300-301	2/2006	KR		
128	903-905	2/2006	KR		

SEARCH NOTES					
Search Notes	Date	Examiner			
Search updated	2/2006	KR			

INTERFERENCE SEARCH						
Class	Subclass	Date	Examiner			